UP03397

Silicon NPN epitaxial planar type (Tr1) Silicon PNP epitaxial planar type (Tr2)

For digital circuits

Features

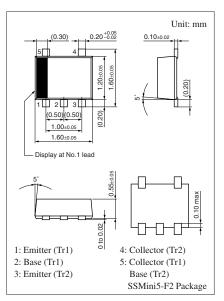
- Two elements incorporated into one package (Transistors with built-in resistor)
- Reduction of the mounting area and assembly cost by one half

Basic Part Number

• UNR1154 + UNR1211

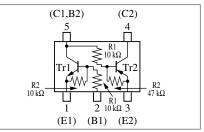
Absolute Maximum Ratings $T_a = 25^{\circ}C$

| | | 0 1 1 | D .:: | |
|---------|---------------------------|------------------|--------------|------|
| | Parameter | Symbol | Rating | Unit |
| Tr1 | Collector-base voltage | V _{CBO} | 50 | V |
| | (Emitter open) | | | |
| | Collector-emitter voltage | V _{CEO} | 50 | V |
| | (Base open) | | | |
| | Collector current | I _C | 100 | mA |
| Tr2 | Collector-base voltage | V _{CBO} | -30 | V |
| | (Emitter open) | | | |
| | Collector-emitter voltage | V _{CEO} | -30 | V |
| | (Base open) | | | |
| | Collector current | I _C | -100 | mA |
| Overall | Total power dissipation | P _T | 125 | mW |
| | Junction temperature | Tj | 125 | °C |
| | Storage temperature | T _{stg} | -55 to +125 | °C |



Marking Symbol: 3M

Internal Connection



\blacksquare Electrical Characteristics $T_a = 25^{\circ}C \pm 3^{\circ}C$

• Tr1

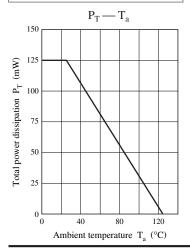
| Parameter | Symbol | Conditions | Min | Тур | Max | Unit |
|--|---------------------------------|---|------|-----|------|------|
| Collector-base voltage (Emitter open) | V _{CBO} | $I_{\rm C} = 10 \ \mu A, \ I_{\rm E} = 0$ | 50 | | | V |
| Collector-emitter voltage (Base open) | V _{CEO} | $I_{\rm C} = 2 \text{ mA}, I_{\rm B} = 0$ | 50 | | | V |
| Collector-base cutoff current (Emitter open) | I _{CBO} | $V_{CB} = 50 \text{ V}, I_E = 0$ | | | 0.1 | μΑ |
| Collector-emitter cutoff current (Base open) | I _{CEO} | $V_{CE} = 50 \text{ V}, I_B = 0$ | | | 0.5 | μΑ |
| Emitter-base cutoff current (Collector open) | I _{EBO} | $V_{EB} = 6 V, I_C = 0$ | | | 0.5 | mA |
| Forward current transfer ratio | h _{FE} | $V_{CE} = 10 \text{ V}, \text{ I}_{C} = 5 \text{ mA}$ | 35 | | | |
| Collector-emitter saturation voltage | V _{CE(sat)} | $I_{\rm C} = 10 \text{ mA}, I_{\rm B} = 0.3 \text{ mA}$ | | | 0.25 | V |
| Output voltage high-level | V _{OH} | $V_{CC} = 5 \text{ V}, V_{B} = 0.5 \text{V}, \text{R}_{L} = 1 \text{k}\Omega$ | 4.9 | | | V |
| Output voltage low-level | V _{OL} | $V_{CC} = 5 \text{ V}, V_{B} = 2.5 \text{ V}, \text{R}_{L} = 1 \text{k}\Omega$ | | | 0.2 | V |
| Input resistance | R ₁ | | -30% | 10 | +30% | kΩ |
| Resistance ratio | R ₁ / R ₂ | | 0.8 | 1.0 | 1.2 | |
| Transition frequency | f _T | $V_{CB} = 10 \text{ V}, I_E = -2 \text{ mA}, f = 200 \text{ MHz}$ | | 150 | | MHz |

Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors. • Tr2

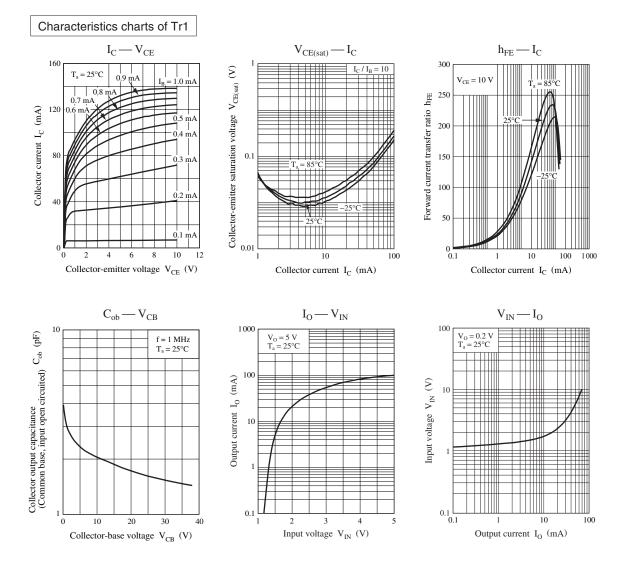
| Parameter | Symbol | Conditions | Min | Тур | Max | Unit |
|--|---------------------------------|--|------|-------|-------|------|
| Collector-base voltage (Emitter open) | V _{CBO} | $I_{\rm C} = -10 \ \mu {\rm A}, \ I_{\rm E} = 0$ | -30 | | | V |
| Collector-emitter voltage (Base open) | V _{CEO} | $I_{\rm C} = -2 \text{ mA}, I_{\rm B} = 0$ | -30 | | | V |
| Collector-base cutoff current (Emitter open) | I _{CBO} | $V_{CB} = -30 \text{ V}, I_E = 0$ | | | - 0.1 | μΑ |
| Collector-emitter cutoff current (Base open) | I _{CEO} | $V_{CE} = -30 \text{ V}, I_B = 0$ | | | - 0.5 | μΑ |
| Emitter-base cutoff current (Collector open) | I _{EBO} | $V_{EB} = -3 V, I_C = 0$ | | | - 0.1 | mA |
| Forward current transfer ratio | h _{FE} | $V_{CE} = -10 \text{ V}, I_C = -5 \text{ mA}$ | 80 | | | — |
| Collector-emitter saturation voltage | V _{CE(sat)} | $I_{\rm C} = -50$ mA, $I_{\rm B} = -0.33$ mA | | | -1.2 | V |
| Output voltage high-level | V _{OH} | $V_{CC} = -5 \text{ V}, V_B = -0.5 \text{ V}, R_L = 1 \text{ k}\Omega$ | -4.9 | | | V |
| Output voltage low-level | V _{OL} | $V_{CC} = -5 \text{ V}, V_B = -2.5 \text{ V}, R_L = 1 \text{ k}\Omega$ | | | - 0.2 | V |
| Input resistance | R ₁ | | -30% | 10 | +30% | kΩ |
| Resistance ratio | R ₁ / R ₂ | | | 0.213 | | — |
| Transition frequency | f _T | $V_{CB} = -10 \text{ V}, I_E = 1 \text{ mA}, f = 200 \text{ MHz}$ | | 80 | | MHz |

Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

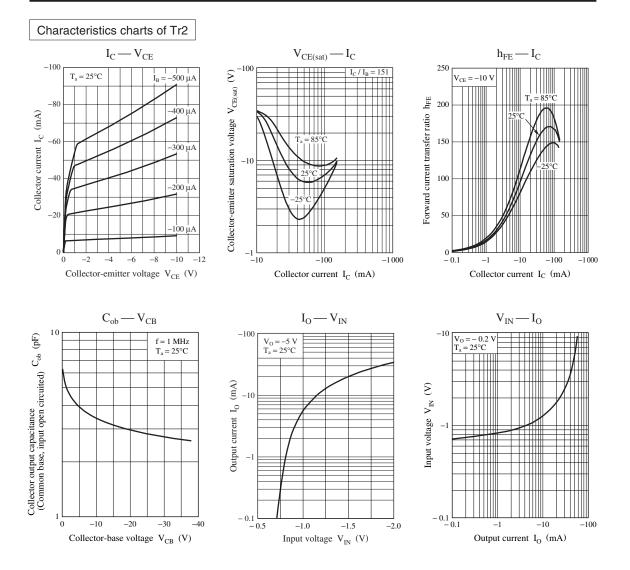
Common characteristics chart



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